Search Notes



Application/Control No.

10572752

Reexamination
NAKAMURA ET AL.

Examiner

Art Unit

Applicant(s)/Patent Under

Examiner

Jennifer F Chang

SEARCHED

SEARCHED						
Class	Subclass	Date	Examiner			
343	788	11/13/2007	Jennifer F. Chang			
343	787	11/19/2008	Jennifer F. Chang			

SEARCH NOTES

Search Notes	Date	Examiner
EAST Search History	11/13/2007	Jennifer F. Chang
Inventor Search in eDAN	11/13/2007	Jennifer F. Chang
EAST Search History	6/5/2008	Jennifer F. Chang

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner	

/JENNIFER F CHANG/ Examiner.Art Unit 2821

U.S. Patent and Trademark Office Part of Paper No.: 20081112